

Notice of References Cited	Application/Control No. 10/611,896	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Thien F. Tran	Art Unit 2811	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,995,187	11-1999	Wakagi et al.	349/141
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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